











SN74LV4046A

SCES656E - FEBRUARY 2006-REVISED NOVEMBER 2016

# SN74LV4046A High-Speed CMOS Logic Phase-Locked Loop With VCO

#### **Features**

- ESD Protection Exceeds JESD 22
  - 2000-V Human Body Model (A114-A)
  - 1000-V Charged-Device Model (C101)
- Choice of Three Phase Comparators
  - Exclusive OR
  - Edge-Triggered J-K Flip-Flop
  - Edge-Triggered RS Flip-Flop
- **Excellent VCO Frequency Linearity**
- VCO-Inhibit Control for ON/OFF Keying and for Low Standby Power Consumption
- Optimized Power-Supply Voltage Range From 3 V to 5.5 V
- Wide Operating Temperature Range From –40°C to +125°C
- Latch-Up Performance Exceeds 250 mA Per JESD 17

# Applications

- **Telecommunications**
- Signal Generators
- Digital Phase-Locked Loop

#### 3 Description

The SN74LV4046A is a high-speed silicon-gate CMOS device that is pin compatible with the CD4046B and the CD74HC4046. The device is specified in compliance with JEDEC Std 7.

The SN74LV4046A is a phase-locked loop (PLL) circuit that contains a linear voltage-controlled oscillator (VCO) and three different comparators (PC1, PC2, and PC3). A signal input and a comparator input are common to each comparator.

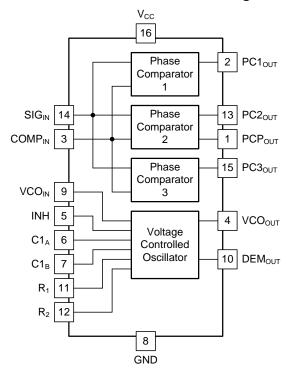
The signal input can be directly coupled to large voltage signals, or indirectly coupled (with a series capacitor) to small voltage signals. A self-bias input circuit keeps small voltage signals within the linear region of the input amplifiers. With a passive lowpass filter, the SN74LV4046A forms a second-order loop PLL. The excellent VCO linearity is achieved by the use of linear operational amplifier techniques. Various applications include telecommunications, digital phase-locked loop and signal generators.

## Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)
SN74LV4046ANS	SO (16)	7.70 mm × 10.20 mm
SN74LV4046AD	SOIC (16)	6.00 mm × 9.90 mm
SN74LV4046APW	TSSOP (16)	6.40 mm × 5.00 mm
SN74LV4046ADGVR	TVSOP (16)	3.60 mm × 4.40 mm
SN74LV4046AN	PDIP (16)	19.30 mm × 6.35 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

### SN74LV4046A Functional Block Diagram





## **Table of Contents**

1	Features 1		7.4 Device Functional Modes	
2	Applications 1	8	Application and Implementation	
3	Description 1		8.1 Application Information	12
4	Revision History2		8.2 Typical Application	12
5	Pin Configuration and Functions 3	9	Power Supply Recommendations	14
6	Specifications4	10	Layout	
	6.1 Absolute Maximum Ratings 4		10.1 Layout Guidelines	14
	6.2 ESD Ratings		10.2 Layout Example	14
	6.3 Recommended Operating Conditions	11	Device and Documentation Support	1
	6.4 Thermal Information		11.1 Documentation Support	1
	6.5 Electrical Characteristics		11.2 Receiving Notification of Documentation Updates	1
	6.6 Switching Characteristics		11.3 Community Resources	1
	6.7 Typical Characteristics9		11.4 Trademarks	1
7	Detailed Description 10		11.5 Electrostatic Discharge Caution	1
-	7.1 Overview		11.6 Glossary	1
	7.2 Functional Block Diagram	12	Mechanical, Packaging, and Orderable	
	7.3 Feature Description		Information	1

# 4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Ch	anges from Revision D (September 2015) to Revision E	age
•	Deleted 200-V Machine Model (A115-A) from Features	1
•	Added TVSOP and PDIP packages to Device Information table	1
•	Added TVSOP, SO, and PDIP packages to pinout	3
•	Changed R <sub>0JA</sub> for D package from 73°C/W to 82.8°C/W	4
•	Changed R <sub>0JA</sub> for DGV package from 120°C/W to 116.8°C/W	4
•	Changed R <sub>BJA</sub> for NS package from 64°C/W to 83.5°C/W	4
•	Changed R <sub>0JA</sub> for PW package from 108°C/W to 108.1°C/W	4
•	Added values in the <i>Thermal Information</i> table to align with JEDEC standards	
•	Changed x-axis from "–360° 0° 360°" to "0° 90° 180°"	9
•	Changed "(V <sub>CC</sub> /4)" to "(V <sub>CC</sub> /4π)"	9
•	Added Receiving Notification of Documentation Updates section	

## Changes from Revision C (April 2007) to Revision D

Page

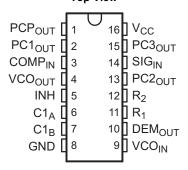
Submit Documentation Feedback

Copyright © 2006–2016, Texas Instruments Incorporated



# 5 Pin Configuration and Functions

D, DGV, NS, N, or PW Package 16-Pin SOIC, TVSOP, SO, PDIP, or TSSOP Top View



#### **Pin Functions**

PIN		1/0	DESCRIPTION
NO.	NAME	I/O	DESCRIPTION
1	PCP <sub>OUT</sub>	0	Phase comparator pulse output
2	PC1 <sub>OUT</sub>	0	Phase comparator 1 output
3	COMP <sub>IN</sub>	I	Comparator input
4	VCO <sub>OUT</sub>	0	VCO output
5	INH	1	Inhibit input
6	C1 <sub>A</sub>	_	Capacitor C1 connection A
7	C1 <sub>B</sub>		Capacitor C1 connection B
8	GND	_	Ground (0 V)
9	VCO <sub>IN</sub>	1	VCO input
10	DEM <sub>OUT</sub>	0	Demodulator output
11	R <sub>1</sub>	_	Resistor R1 connection
12	R <sub>2</sub>	_	Resistor R2 connection
13	PC2 <sub>OUT</sub>	0	Phase comparator 2 output
14	SIG <sub>IN</sub>	1	Signal input
15	PC3 <sub>OUT</sub>	0	Phase comparator 3 output
16	V <sub>CC</sub>	_	Positive supply voltage



# 6 Specifications

### 6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

			MIN	MAX	UNIT
$V_{CC}$	DC supply voltage		-0.5	7	V
$V_{I}$	Input voltage		-0.5	$V_{CC} + 0.5$	V
Vo	Output voltage		-0.5	$V_{CC} + 0.5$	V
I <sub>IK</sub>	Input clamp current	V <sub>I</sub> < 0		-20	mA
I <sub>OK</sub>	Output clamp current	V <sub>O</sub> < 0		-50	mA
Io	Continuous output curent	$V_O = 0$ to $V_{CC}$		±35	mA
I <sub>CC</sub>	DC V <sub>CC</sub> or ground current			±70	mA
TJ	Junction temperature			150	ô
T <sub>stg</sub>	Storage temperature		<del>-</del> 65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

# 6.2 ESD Ratings

			VALUE	UNIT
V		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 <sup>(1)</sup>		\/
V <sub>(ESD)</sub> Electrostatic disch	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 (2)	±1000	V

<sup>(1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

# 6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
T <sub>A</sub>	Operating free-air temperature	-40	125	°C
V <sub>CC</sub>	Supply voltage	3	5.5	V
V <sub>I</sub> , V <sub>O</sub>	DC input or output voltage	0	V <sub>CC</sub>	V

#### 6.4 Thermal Information

		SN74LV4046A						
	THERMAL METRIC <sup>(1)</sup>	D (SOIC)	DGV (TVSOP)	NS (SO)	PW (TSSOP)	N (PDIP)	UNIT	
		16 PINS	16 PINS	16 PINS	16 PINS	16 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	82.8	116.8	83.5	108.1	49.4	°C/W	
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	44.0	43.3	41.7	42.7	36.7	°C/W	
$R_{\theta JB}$	Junction-to-board thermal resistance	40.3	48.3	43.8	53.1	29.3	°C/W	
ΨЈТ	Junction-to-top characterization parameter	11.1	3.7	9.3	4.2	21.5	°C/W	
ΨЈВ	Junction-to-board characterization parameter	40.0	47.8	43.5	52.5	29.2	°C/W	

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



#### 6.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

				TEST COND	ITIONS					
	PARAMET	ΓER		V <sub>1</sub> (V)	I <sub>O</sub> (mA)	V <sub>CC</sub> (V)	MIN	TYP	MAX	UNIT
vco				1()	0 ( )					
						3 to 3.6	V <sub>CC</sub> × 0.7			
V <sub>IH</sub>	High-level input voltage	INH					V <sub>CC</sub> × 0.7			V
.,						3 to 5.5			V <sub>CC</sub> × 0.3	.,
$V_{IL}$	Low-level input voltage	INH				4.5 to 5.5			$V_{CC} \times 0.3$	V
			CMOS		0.05	3 to 3.6	V <sub>CC</sub> - 0.1			
$V_{OH}$	High-level output voltage	VCO <sub>OUT</sub>	CMOS	$V_{IL}$ or $V_{IH}$	-0.05	4.5 to 5.5	V <sub>CC</sub> - 0.1			V
			TTL		-12	4.5 to 5.5	3.8			
			CMOS		0.05	3 to 3.6			0.1	
	Low-level	VCO <sub>OUT</sub>	CIVIOO		0.03	4.5 to 5.5			0.1	
$V_{OL}$	output voltage		TTL	V <sub>IL</sub> or V <sub>IH</sub>	12	4.5 to 5.5			0.55	V
		C1A, C1B (test purpo	ses only)		12	4.5 to 5.5			0.65	
l <sub>l</sub>	Input leakage current	INH, VCO <sub>II</sub>	N	V <sub>CC</sub> or GND		5.5			±1	μА
-	R1 range <sup>(1)</sup>					3 to 5.5	3		50	kΩ
	R2 range <sup>(1)</sup>					3 to 5.5	3		50	kΩ
	C1 capacitance range					3 to 3.6	40		No Limit	pF
	CT capacitance range					4.5 to 5.5	40		No Limit	pΓ
	Operating voltage range	VCO		Over the range s		3 to 3.6	1.1		1.9	V
	Operating voltage range VCO <sub>IN</sub>			R1 for linearity <sup>(2)</sup>		4.5 to 5.5	1.1		3.2	V
PHASE	COMPARATOR									
V <sub>IH</sub>	DC-coupled high-level		SIG <sub>IN</sub> ,			3 to 3.6	V <sub>CC</sub> × 0.7			
VIН	input voltage		COMP <sub>IN</sub>			4.5 to 5.5	$V_{CC} \times 0.7$			
V <sub>IL</sub>	DC-coupled low-level input	voltage	SIG <sub>IN</sub> ,			3 to 3.6			$V_{CC} \times 0.3$	V
• IL	20 coapioa ion ioro: inpat	Tomago	COMPIN			4.5 to 5.5			$V_{CC} \times 0.3$	
	High-level	DCD.	CMOS		-0.05	3 to 5.5	V <sub>CC</sub> - 0.1			
V <sub>OH</sub>	output voltage	PCP <sub>OUT</sub> , PCN <sub>OUT</sub>		V <sub>IL</sub> or V <sub>IH</sub>	-6	3 to 3.6	2.48			V
			TTL		-12	4.5 to 5.5	3.8			
	Lowloyd	DCD	CMOS		0.02	3 to 3.6			0.1	
$V_{OL}$	Low-level output voltage	PCP <sub>OUT</sub> , PCN <sub>OUT</sub>	000	$V_{\text{IL}}$ or $V_{\text{IH}}$		4.5 to 5.5			0.1	V
			TTL		4	4.5 to 5.5			0.4	
ı.	Input leakage current		SIG <sub>IN</sub> , COMP <sub>IN</sub>	V <sub>CC</sub> or GND		3 to 3.6			±11	., ^
ı	input icakaye current			ACC OL GIAD		4.5 to 5.5			±29	μА
l <sub>oz</sub>	3-state off-state current		PC2 <sub>OUT</sub>	V <sub>IL</sub> or V <sub>IH</sub>		3 to 5.5			±5	μΑ
R <sub>I</sub>	Input resistance		SIG <sub>IN</sub> ,	V <sub>I</sub> at self-bias		3		800		kΩ
•	·		COMPIN	point, V <sub>I</sub> =	0.5 V	4.5		250		
DEMOI	DULATOR				Т					
R <sub>S</sub>	Resistor range			R <sub>S</sub> > 300 kΩ, Leakage current can influence		3 to 3.6	50		300	kΩ
``S	resistor range			V <sub>DEMO</sub>		4.5 to 5.5	50		300	1/22
	Offeet valtege VCO 4- V			$V_I = V_{VCOIN} = V_C$	<sub>CC/2</sub> , Values	3 to 3.6		±30		\/
V <sub>OFF</sub>	Offset voltage VCO <sub>IN</sub> to V <sub>D</sub>	EM		taken over R	taken over R <sub>S</sub> range			±20		mV
I <sub>cc</sub>	Quiescent device current			Pins 3, 5, and Pin 9 at GND, and 14 to be	l <sub>I</sub> at pins 3	5.5			50	μΑ

Copyright © 2006–2016, Texas Instruments Incorporated

Submit Documentation Feedback

<sup>(1)</sup> The value for R1 and R2 in parallel should exceed 2.7 k $\Omega$ . (2) The maximum operating voltage can be as high as  $V_{CC} - 0.9 \text{ V}$ ; however, this may result in an increased offset voltage.



# 6.6 Switching Characteristics

over operating free-air temperature range (unless otherwise noted)  $C_L = 50$  pF, Input  $t_r$ ,  $t_f = 6$  ns

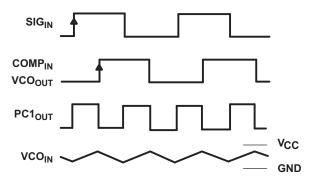
	PARAMETER		TEST CONDITIONS	V <sub>CC</sub> (V)	MIN TYP	MAX	UNIT
PHASE CON	MPARATOR						
	Dropogation delay	SIG <sub>IN</sub> , COMP <sub>IN</sub> to		3 to 3.6		135	20
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	PC1 <sub>OUT</sub>		4.5 to 5.5		50	ns
	Dropogation delay	SIGIN, COMP <sub>IN</sub> to		3 to 3.6		300	20
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	PCP <sub>OUT</sub>		4.5 to 5.5		60	ns
	Dronagation delay	SIG <sub>IN</sub> , COMP <sub>IN</sub> to		3 to 3.6		200	no
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	PC3 <sub>OUT</sub>		4.5 to 5.5		50	ns
<b>+</b>	Output transition time			3 to 3.6		75	ns
t <sub>THL</sub> , t <sub>TLH</sub>	Output transition time			4.5 to 5.5		15	115
t t	3-state output enable time	SIG <sub>IN</sub> , COMP <sub>IN</sub> to		3 to 3.6		270	ns
t <sub>PZH</sub> , t <sub>PZL</sub>	5-state output enable time	PC2 <sub>OUT</sub>		4.5 to 5.5		54	115
t t	3-state output disable time	SIG <sub>IN</sub> , COMP <sub>IN</sub> to		3 to 3.6		320	ns
$t_{PHZ}, t_{PLZ}$	5-state output disable time	PC2OUT		4.5 to 5.5		65	113
	AC-coupled input sensitivity	(P-P) at SIG <sub>IN</sub> or	$V_{I(P-P)}$	3 to 3.6	11		mV
	AC-coupled input sensitivity	COMP <sub>IN</sub>	V I(P-P)	4.5 to 5.5	15		IIIV
vco							
		$V_{I} = VCO_{IN} = 1/2 V_{CC},$	3 to 3.6	0.11			
Δf/ΔΤ	Frequency stability with tempe	$R_1 = 100 \text{ k}\Omega,$ $R_2 = \infty,$ $C_1 = 100 \text{ pF}$	4.5 to 5.5	0.11		%/°C	
					24		
		$R_1 = 3.5 \text{ k}\Omega,$ $R_2 = \infty$ $C_1 = 0 \text{ pF},$ $R_1 = 9.1 \text{ k}\Omega,$ $R2 = \infty$	4.5 to 5.5	24		MHz	
$f_{MAX}$	Maximum frequency		3 to 3.6	38			
			4.5 to 5.5	38			
			$C_1 = 40 \text{ pF},$ $R_1 = 3 \text{ k}\Omega,$	3 to 3.6	7 10		-
	Center frequency (duty 50%)		$R_2 = \infty$ ,	4.5 to 5.5	12 17	(4)	MHz
			$VCO_{IN} = V_{CC}/2$	4.5 <sup>(1)</sup>	15 <sup>(1)</sup>	17.5 <sup>(1)</sup>	
ΔfVCO	Frequency linearity		$C_1 = 100 \text{ pF},$ $R_1 = 100 \text{ k}\Omega,$	3 to 3.6	0.4%		
ДІЛСО	riequency inleanty		$R_1 = 100 \text{ K}\Omega$ , $R_2 = \infty$	4.5 to 5.5	0.4%		
	0"		$C_1 = 1 \text{ nF},$	3 to 3.6	400		
	Offset frequency		$R_2 = 220 \text{ k}\Omega$	4.5 to 5.5	400		kHz
DEMODULA	TOR						
			$C_1 = 100 \text{ pF},$	3	8		
V <sub>OUT</sub> vs f <sub>IN</sub>			$C_2 = 100 \text{ pF},$ $R_1 = 100 \text{ k}\Omega,$ $R_2 = \infty,$ $R_3 = 100 \text{ k}\Omega$	4.5	330		mV/kHz

<sup>(1)</sup> Data is specified at 25°C

Submit Documentation Feedback

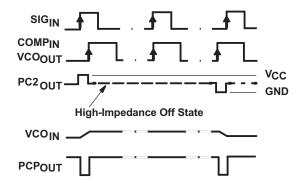
Copyright © 2006–2016, Texas Instruments Incorporated





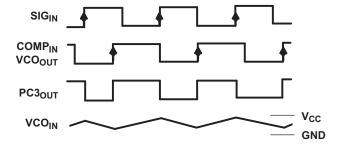
Loop Locked at fo

Figure 1. Typical Waveforms for PLL Using Phase Comparator 1



Loop Locked at fo

Figure 2. Typical Waveforms for PLL Using Phase Comparator 2



Loop Locked at fo

Figure 3. Typical Waveforms for PLL Using Phase Comparator 3



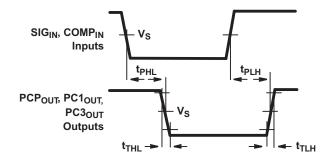


Figure 4. Input-to-Output Propagation Delays and Output Transition Times

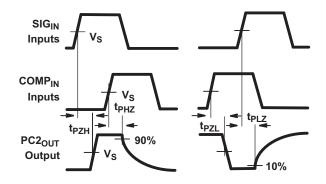
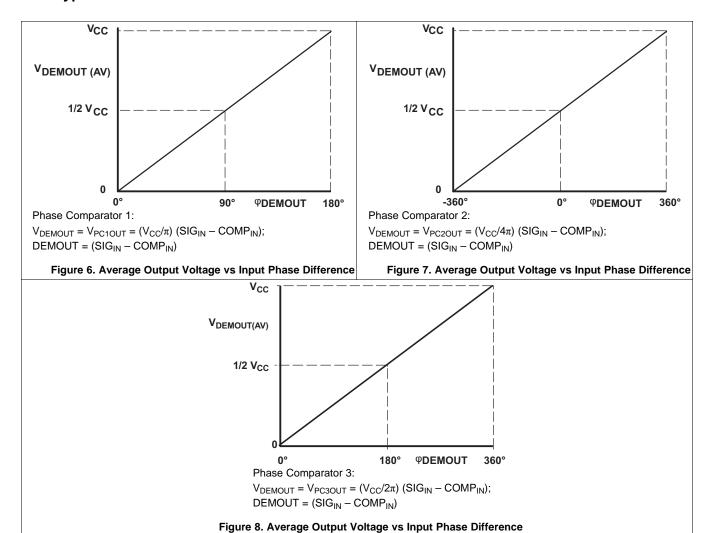


Figure 5. 3-State Enable and Disable Times for PC2<sub>OUT</sub>



# 6.7 Typical Characteristics



Submit Documentation Feedback



# 7 Detailed Description

#### 7.1 Overview

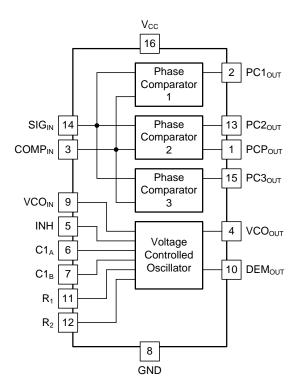
The SN74LV4046A is a high-speed silicon-gate CMOS device that is pin compatible with the CD4046B and the CD74HC4046. The device is specified in compliance with JEDEC Std 7.

The SN74LV4046A is a phase-locked loop (PLL) circuit that contains a linear voltage-controlled oscillator (VCO) and three different phase comparators (PC1, PC2, and PC3) as explained in the *Features* section. A signal input and a comparator input are common to each comparator as shown in the *Functional Block Diagram*.

The signal input can be directly coupled to large voltage signals, or indirectly coupled (with a series capacitor) to small voltage signals. A self-bias input circuit keeps small voltage signals within the linear region of the input amplifiers. With a passive lowpass filter, the SN74LV4046A forms a second-order loop PLL. The excellent VCO linearity is achieved by the use of linear operational amplifier techniques. Various applications include telecommunications, Digital Phase Locked Loop and Signal generators.

The VCO requires one external capacitor C1 (between C1A and C1B) and one external resistor R1 (between R1 and GND) or two external resistors R1 and R2 (between R1 and GND, and R2 and GND). Resistor R1 and capacitor C1 determine the frequency range of the VCO. Resistor R2 enables the VCO to have a frequency offset if required. The high input impedance of the VCO simplifies the design of lowpass filters by giving the designer a wide choice of resistor or capacitor ranges. In order to not load the lowpass filter, a demodulator output of the VCO input voltage is provided at pin 10 (DEM<sub>OUT</sub>). In contrast to conventional techniques where the DEM<sub>OUT</sub> voltage is one threshold voltage lower than the VCO input voltage, here the DEM<sub>OUT</sub> voltage equals that of the VCO input. If DEM<sub>OUT</sub> is used, a load resistor (R<sub>S</sub>) should be connected from DEM<sub>OUT</sub> to GND; if unused, DEM<sub>OUT</sub> should be left open. The VCO output (VCO<sub>OUT</sub>) can be connected directly to the comparator input (COMP<sub>IN</sub>), or connected through a frequency divider. The VCO output signal has a specified duty factor of 50%. A LOW level at the inhibit input (INH) enables the VCO and demodulator, while a HIGH level turns both off to minimize standby power consumption.

#### 7.2 Functional Block Diagram



Submit Documentation Feedback

Copyright © 2006–2016, Texas Instruments Incorporated



#### 7.3 Feature Description

There are three choices for the Phase Comparators in this device which are listed as follows:

- Phase comparator 1 (PC1) is an Exclusive OR network. The average output voltage from PC1, fed to VCO input through the low pass filter and seen at the demodulator output at pin 10 (V<sub>DEMOUT</sub>), is the resultant of the phase differences of signals (SIG<sub>IN</sub>) and the compartor input (COMP<sub>IN</sub>) as shown in Figure 7. The average of V<sub>DEM</sub> is equal to 1/2 VCC when there is no signal or noise at SIG<sub>IN</sub>, and with this input the VCO oscillates at the center frequency (fo).
- Phase comparator 2 (PC2) is an Edge-Triggered Flip-Flop. This is a positive edge-triggered phase and frequency detector. When the PLL is using this comparator, the loop is controlled by positive signal transitions and the duty factors of SIG<sub>IN</sub> and COMP<sub>IN</sub> are not important. PC2 comprises two D-type flip-flops, controlgating and a three-state output stage. The circuit functions as an up-down counter where SIG<sub>IN</sub> causes an up-count and COMP<sub>IN</sub> a down-count. The average output voltage from PC2, fed to the VCO through the lowpass filter and seen at the demodulator output at pin 10 (V<sub>DEMOUT</sub>), is the resultant of the phase differences of SIG<sub>IN</sub> and COMP<sub>IN</sub>as in Figure 8.
- Phase comparator 3 (PC3) is an positive Edge-Triggered RS Flip-Flop. This is a positive edge-triggered sequential phase detector using an RS-type flip-flop. When the PLL is using this comparator, the loop is controlled by positive signal transitions and the duty factors of SIG<sub>IN</sub> and COMP<sub>IN</sub> are not important. The average output from PC3, fed to the VCO through the lowpass filter and seen at the demodulator at pin 10 (V<sub>DEMOLIT</sub>), is the resultant of the phase differences of SIG<sub>IN</sub> and COMP<sub>IN</sub> as shown in Figure 9.

The excellent VCO linearity is achieved by the use of linear operational amplifier techniques. It has low standby power consumption using VCO inhibit control. Wide operating temperature range from -40°C to +125°C along with an optimized power supply voltage range from 3 V to 5.5 V.

#### 7.4 Device Functional Modes

The SN74LV4046A device does not feature any special functional modes.



# 8 Application and Implementation

#### **NOTE**

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

# 8.1 Application Information

The most common use for the digital phased-locked loop (PLL) device is to match the VCO output to the same phase as the incoming signal and produce an error signal (DEM<sub>OUT</sub>) that indicates the amount of phase shift required for the match. This can be used as part of many complex systems.

## 8.2 Typical Application

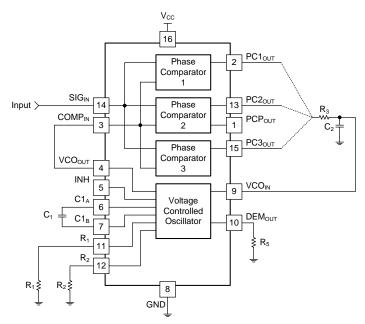


Figure 9. SN74LV4046A Digital Clock Signal Phase Comparison Application

Submit Documentation Feedback



# **Typical Application (continued)**

#### 8.2.1 Design Requirements

Table 1 and Table 2 lists the design requirements of the SN74LV4046A.

Table 1. Component Selection Criteria<sup>(1)</sup>

COMPONENT	VALUE
R1	3 kΩ to 50 kΩ
R2	3 kΩ to 50 kΩ
R1    R2	> 2.7 kΩ
C1	> 40 pF
R3	1 kΩ
C2	1 uF
R5	50 kΩ to 300 kΩ

(1) R1 between 3 k $\Omega$  and 50 k $\Omega$  R2 between 3 k $\Omega$  and 50 k $\Omega$  R1 + R2 parallel value > 2.7 k $\Omega$  C1 > 40 pF

Table 2. C<sub>PD</sub><sup>(1)</sup>

CHIP SECTION	C <sub>PD</sub>	UNIT
Comparator 1	120	۲
VCO	120	p⊦

(1) R1 between 3 k $\Omega$  and 50 k $\Omega$ R2 between 3 k $\Omega$  and 50 k $\Omega$ R1 + R2 parallel value > 2.7 k $\Omega$ C1 > 40 pF

## 8.2.2 Detailed Design Procedure

- 1. Recommended Input Conditions:
  - V<sub>IH</sub> and V<sub>IL</sub> for each input can be found in *Electrical Characteristics*.
- 2. Recommended Output Conditions:
  - Valid load resistor values are specified in Electrical Characteristics.
- 3. Frequency Selection Criterion:
  - Frequency data is found in *Electrical Characteristics*.

# 8.2.3 Application Curves

Table 3 lists the application curves in the *Typical Characteristics* section.

**Table 3. Table of Graphs** 

GRAPH TITLE	FIGURE
Average Output Voltage vs Input Phase Difference	Figure 6
Average Output Voltage vs Input Phase Difference	Figure 7
Average Output Voltage vs Input Phase Difference	Figure 8



# 9 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage ratings located in the *Recommended Operating Conditions* table.

Each  $V_{CC}$  pin should have a good bypass capacitor to prevent power disturbance. For devices with a single supply. a 0.1- $\mu$ F capacitor is recommended and if there are multiple  $V_{CC}$  pins then 0.01- $\mu$ F or 0.022- $\mu$ F capacitor is recommended for each power pin. It is ok to parallel multiple bypass capacitors to reject different frequencies of noise. 0.1- $\mu$ F and 1- $\mu$ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power pin as possible for best results.

# 10 Layout

## 10.1 Layout Guidelines

Reflections and matching are closely related to the loop antenna theory but are different enough to be discussed separately from the theory. When a PCB trace turns a corner at a 90° angle, a reflection can occur. A reflection occurs primarily because of the change of width of the trace. At the apex of the turn, the trace width increases to 1.414 times the width. This increase upsets the transmission-line characteristics, especially the distributed capacitance and self–inductance of the trace which results in the reflection. Not all PCB traces can be straight and therefore some traces must turn corners. Figure 10 shows progressively better techniques of rounding corners. Only the last example (BEST) maintains constant trace width and minimizes reflections.

#### 10.2 Layout Example

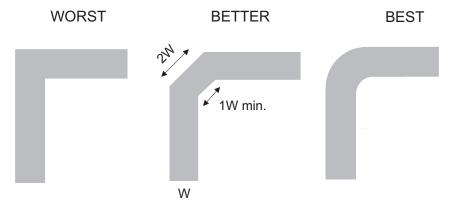


Figure 10. Trace Example

Submit Documentation Feedback



# 11 Device and Documentation Support

## 11.1 Documentation Support

#### 11.1.1 Related Documentation

For related documentation see the following:

Implications of Slow or Floating CMOS Inputs, SCBA004

# 11.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 11.3 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

**Design Support** *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

#### 11.4 Trademarks

E2E is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

### 11.5 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

#### 11.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

# 12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.





26-Oct-2016

#### **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	_	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
SN74LV4046AD	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	LV4046A	Samples
SN74LV4046ADG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	LV4046A	Samples
SN74LV4046ADGVR	ACTIVE	TVSOP	DGV	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	LW046A	Samples
SN74LV4046ADR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	LV4046A	Samples
SN74LV4046ADRG4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	LV4046A	Samples
SN74LV4046AN	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-40 to 85	SN74LV4046AN	Samples
SN74LV4046ANE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-40 to 85	SN74LV4046AN	Samples
SN74LV4046ANS	ACTIVE	so	NS	16	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	74LV4046A	Samples
SN74LV4046ANSR	ACTIVE	SO	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	74LV4046A	Samples
SN74LV4046APW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	LW046A	Samples
SN74LV4046APWG4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	LW046A	Samples
SN74LV4046APWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	LW046A	Samples
SN74LV4046APWRG4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	LW046A	Samples

<sup>(1)</sup> The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.



# PACKAGE OPTION ADDENDUM

26-Oct-2016

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

# PACKAGE MATERIALS INFORMATION

www.ti.com 26-Oct-2016

# TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

All differsions are norminal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74LV4046ADGVR	TVSOP	DGV	16	2000	330.0	12.4	6.8	4.0	1.6	8.0	12.0	Q1
SN74LV4046ADR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
SN74LV4046ANSR	SO	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
SN74LV4046APWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

www.ti.com 26-Oct-2016



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74LV4046ADGVR	TVSOP	DGV	16	2000	367.0	367.0	35.0
SN74LV4046ADR	SOIC	D	16	2500	333.2	345.9	28.6
SN74LV4046ANSR	SO	NS	16	2000	367.0	367.0	38.0
SN74LV4046APWR	TSSOP	PW	16	2000	367.0	367.0	35.0

# D (R-PDS0-G16)

# PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



# D (R-PDSO-G16)

# PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



# **MECHANICAL DATA**

# NS (R-PDSO-G\*\*)

# 14-PINS SHOWN

## PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



PW (R-PDSO-G16)

# PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



# PW (R-PDSO-G16)

# PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



# N (R-PDIP-T\*\*)

# PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



#### IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have *not* been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

#### Products Applications

Audio www.ti.com/audio Automotive and Transportation www.ti.com/automotive **Amplifiers** amplifier.ti.com Communications and Telecom www.ti.com/communications **Data Converters** dataconverter.ti.com Computers and Peripherals www.ti.com/computers **DLP® Products** www.dlp.com Consumer Electronics www.ti.com/consumer-apps DSP dsp.ti.com **Energy and Lighting** www.ti.com/energy Clocks and Timers www.ti.com/clocks Industrial www.ti.com/industrial Interface interface.ti.com Medical www.ti.com/medical Logic Security www.ti.com/security logic.ti.com

Power Mgmt power.ti.com Space, Avionics and Defense www.ti.com/space-avionics-defense

Microcontrollers microcontroller.ti.com Video and Imaging www.ti.com/video

RFID www.ti-rfid.com

OMAP Applications Processors www.ti.com/omap TI E2E Community e2e.ti.com

Wireless Connectivity www.ti.com/wirelessconnectivity